

4 Temperature Zone All-in-One Testing System

It can meet the Material Manufacturers, Universities and Research Institutes of multiple temperature testing requirements for Coin Cells.

- ◆ Cycle Life Test, Rate Charging / Discharging Test, GITT Test, DCIR Test, Temperature Capability, Reliability Experiment, etc.
- ◆ Integrated and connected with BTS by communication protocol, could set different temperatures and work steps.



Space Saving
 $< 0.5m^2$



Voltage & Current Accuracy
 $\pm 0.05\% \text{ F.S.}$



Sampling Time
 100ms



Number of Channels (Coin Cells)
 $4 \times 16CH$



Temperature Range & Deviation
 $15^\circ C \sim 60^\circ C \pm 2.0^\circ C$
 (No Load & Stable Temperature)



Temperature Fluctuation
 $\leq 1^\circ C$
 (No Load & Stable Temperature)



Heating Time
 $25^\circ C \sim 60^\circ C (\leq 40min)$
 (No Load & Stable Temperature)



Cooling Time
 $25^\circ C \sim 15^\circ C (\leq 60min)$
 (No Load & Stable Temperature)

Voltage & Current	Range	Range 1	Range 2	Range 3
5V/10V10mA		5 $\mu A \sim 1mA$	1mA $\sim 5mA$	5mA $\sim 10mA$
5V/10V20mA		5 $\mu A \sim 1mA$	1mA $\sim 10mA$	10mA $\sim 20mA$
5V/10V50mA		5 $\mu A \sim 1mA$	1mA $\sim 25mA$	25mA $\sim 50mA$

*Other models can be customized according to voltage and current requirements.



Model: MHW-25-S-16CH
 (It can be flexibly split and used separately)



LabTech



Store



Client



Step



DataAnalyzer



Edge



LIMS



Analytics



Report



Calibration



Tele-Control & Tech-Support

Smart-Lab Solutions Platform



Tailor-Made & Worry-Free

One-Stop Purchasing Platform